

TABLE A—SOFT ERRORS AT VARIOUS PROCESS NODES

Process node	Application	Sensitivity to soft errors
0.25 micron	Consumer	None
	Networking/storage	None
	Aerospace/military	Memory and logic
0.18 to 0.13 micron	Consumer	None
	Networking/storage	Memory
	Aerospace/military	Memory and logic
90 nm	Consumer	Memory and logic
	Networking/storage	Memory and logic
	Aerospace/military	Memory and logic
65 nm and below	Consumer	Memory and logic
	Networking/storage	Memory and logic
	Aerospace/military	Memory and logic